WHAT IS CLAIMED IS:

1. A computer-implemented method, comprising correlating a backside defect detected on a specimen with a frontside defect detected on the specimen if a portion of the backside defect on a backside of the specimen is opposite to a portion of the frontside defect on a frontside of the specimen.

2. The method of claim 1, wherein the portion of the backside defect is aligned with the portion of the frontside defect along an axis perpendicular to the frontside and the backside of the specimen.

3. The method of claim 1, further comprising generating a single visual representation of the specimen that illustrates the backside defect and the frontside defect with different formatting to visually differentiate the backside defect and the frontside defect.

4. The method of claim 1, further comprising identifying data representative of a signature of a chuck of a process tool within data generated during detection of the backside defect and removing the data representative of the signature of the chuck from the data generated during detection of the backside defect prior to said correlating.

5. The method of claim 1, further comprising generating visual representations of the frontside and the backside of the specimen, altering one of the visual representations such that the altered visual representation appears as a mirror image of the one visual representation, and superimposing the altered and the unaltered visual representations to generate an overall visual representation of the specimen.

6. The method of claim 5, further comprising determining if the portion of the backside defect on the backside of the specimen is opposite to the portion of the frontside defect on the frontside of the specimen from the overall visual representation.

7. The method of claim 5, wherein the overall visual representation does not illustrate additional backside defects detected on the specimen and additional frontside defects detected on the specimen, and wherein the additional backside defects are not correlated with the additional frontside defects.

8. The method of claim 1, further comprising comparing coordinates defining a location of the backside defect with coordinates defining a location of the frontside defect to determine if the portion of the backside defect on the backside of the specimen is opposite to the portion of the frontside defect on the frontside of the specimen.

9. The method of claim 8, further comprising altering the coordinates defining the location of the backside defect or the coordinates defining the location of the frontside defect prior to said comparing such that the locations of the backside defect and the frontside defect are defined as if the frontside and backside defects were detected on the same side of the specimen.

10. The method of claim 1, further comprising classifying the backside defect.

11. The method of claim 1, further comprising classifying the backside defect and determining a root cause of the backside defect from data representing processing history of the specimen.

12. The method of claim 1, further comprising classifying the backside defect and determining parameters for classifying the frontside defect from the classification of the backside defect.

13. The method of claim 1, further comprising classifying the backside defect and determining a root cause of the frontside defect from the classification of the backside defect.

14. The method of claim 1, further comprising classifying the backside defect and altering a parameter of a process tool in response to the classification.

15. The method of claim 1, further comprising altering a parameter of a process tool in response to the backside defect to reduce occurrence of the frontside defect on additional specimen processed in the process tool.

16. A computer-implemented method, comprising correlating a backside defect detected on a backside of a specimen with a frontside defect detected on a frontside of the specimen if the backside defect and the frontside defect satisfy one or more proximity criteria.

17. The method of claim 16, further comprising defining the backside defect as a geometrical figure having lateral dimensions larger than the backside defect, wherein the one or more proximity criteria are satisfied if at least a portion of the geometrical figure is opposite to at least a portion of the frontside defect.

18. The method of claim 16, further comprising defining the frontside defect as a geometrical figure having lateral dimensions larger than the frontside defect, wherein the one or more proximity criteria are satisfied if at least a portion of the geometrical figure is opposite to at least a portion of the backside defect.

19. The method of claim 16, wherein the one or more proximity criteria are satisfied if at least a portion of the backside defect is opposite to at least a portion of the frontside defect.

20. A computer-implemented method, comprising analyzing data representing spatial characteristics of backside defects detected on a specimen to classify the backside defects.

21. The method of claim 20, wherein said analyzing comprises spatial signature analysis of the data.

22. The method of claim 20, further comprising determining if data generated during detection of the backside defects is representative of a signature of a chuck of a process tool.